## ELECTROCHEMI CALLY DEPOSITED THIN FILMS OF Bi<sub>2</sub>Te<sub>3</sub> FOR THERMOELECTRIC DEVICE APPLICATIONS

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 $Bi_2Te_3$  is a material that has been used for thermoelectric cooling, and this and related compounds are considered to be among the best materials available for such applications [1,2]. Electrochemical deposition of compound semiconductors is a field that has grown considerably in recent years, primarily with applications to solar cells or optoelectronic. devices [3-S]; application of this technique to fabrication of films of  $Bi_2Te_3$  for thermoelectric. devices follows logically from that work. Electrochemical deposition of  $Bi_2Te_3$  has recently been demonstrated [6,7]. 'J'his paper presents a study of deposition conditions and substrates for fabrication of thin films of  $Bi_2Te_3$  and related compounds,

Bi<sub>2</sub>Te<sub>3</sub> may be deposited potentiostatically from an acidic, aqueous solution of BiO<sup>+</sup> and HTeO<sub>2</sub><sup>+</sup>, and may be deposited on a variety of substrates, including plat inure, nickel, gold and bismuth. We have studied the effect of electrolyte composition, and of deposition potential and current density on composition and grain size of Bi<sub>2</sub>Te<sub>3</sub> films, as well as the effect of different substrate. materials. Films have been deposited from HNO, and H<sub>2</sub>SO<sub>4</sub>/HCl solutions; different acids were used to protect substrates from dissolution. Composition may be varied by changing the relative ratio of BiO<sup>4</sup> and  $HTeO_{2}^{+}$  in solution and by changing the deposition potential and/or current density during deposition, Grain size of the film is dependent on the growth rate, which is in turn, dependent on the current density during deposition. Films ranging in thickness from 500 A to several microns may be made.

 $Bi_2Te_3$  may be deposited as n-type, or 'J'e.-rich films, or as p-type, or **Bi-rich** films.. Previous workers [6,7] have reported both **Bi** [6] and **Te** [7] rich films, and that Bi content in the film is affected by the ratio of Bi to 1°c in the electrodeposition solution and by the current density during deposition, The ratio of Bi to Te in both **Bi** and Te rich films may be outside the usual limits of stoiciometric deviation in single. crystal  $Bi_2Te_3$ . This study has found that there is an effect of **Bi/Te** ratio in the solution, but that deposition potential is the major factor in controlling the composition in deposited films. X-ray diffraction studies and compositional analysis of the films indicate that Bi rich films may be a combination of  $Bi_2Te_3$  and BiTe. Te rich films may contain some elemental Te. The films arc pol ycrystalline with some preferential orientation, The degree of orientation appears to be related to grain size, and does not appear to be related strongly to the orientation of the substrate.

Electrodeposited films have been characterized for thermoelectric properties, including majority carrier concentration (N), resistivity ( $\rho$ ) and Seebeck coefficient ( $\alpha$ ) in order to determine their suitability for use in thermoelectric cooling, These properties correspond well to literature. values of properties measured in single crystal Bi<sub>2</sub>Te<sub>3</sub>. Applications of these films to cooling in electronic devices will be discussed.

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